

PC456L0NIP

* VDE (VDE0884) approved type is also available as an option

■ Features

1. High resistance to noise (CMR:MIN. 15kV/μs)
2. High speed response
(t_{PHL} :MAX.400ns, t_{PLH} :MAX.550ns)
3. Mini-flat package
4. Isolation voltage ($V_{iso(rms)}$):3.75kV)
5. Recognized by UL, file No. E64380 (Model No. PC456L)

■ Applications

1. Programmable controller
2. Inverter

■ Absolute Maximum Ratings

 (T_a=25°C)

	Parameter	Symbol	Rating	Unit
Input	*1 Forward current	I _F	25	mA
	Reverse voltage	V _R	5	V
	*2 Power dissipation	P	45	mW
Output	Supply voltage	V _{CC}	-0.5 to +35	V
	Output voltage	V _O	-0.5 to +35	V
	Output current	I _O	15	mA
	*3 Power dissipation	P _O	100	mW
	*4 Isolation voltage	V _{iso(rms)}	3.75	kV
	Operating temperature	T _{opr}	-40 to +100	°C
	Storage temperature	T _{stg}	-40 to +125	°C
	*5 Soldering temperature	T _{sol}	270	°C

*1 When ambient temperature goes above 70°C, the power dissipation goes down at 0.45mA/°C.

*2 When ambient temperature goes above 70°C, the power dissipation goes down at 0.8mW/°C.

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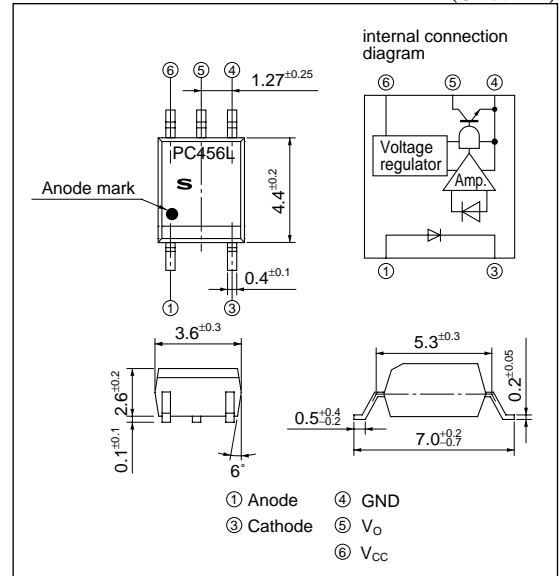
*4 40 to 60%RH, AC for 1minute

*5 For 10s

High Speed and High CMR *OPIC Photocoupler

■ Outline Dimensions

(Unit : mm)



* "OPIC" (Optical IC) is a trademark of the SHARP Corporation. An OPIC consists of a light-detecting element and signal-processing circuit integrated onto a single chip.

■ Electro-optical Characteristics ^{*6}

(unless otherwise specified $T_a=-40$ to 100°C , $V_{CC}=4.5$ to 35V)

	Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit	
Input	Forward voltage	V_F	$T_a=25^\circ\text{C}$, $I_F=10\text{mA}$	–	1.6	1.95	V	
	Reverse current	I_R	$T_a=25^\circ\text{C}$, $V_R=5\text{V}$	–	–	10	μA	
	Terminal capacitance	C_t	$T_a=25^\circ\text{C}$, $V_R=0$, $f=1\text{MHz}$	–	60	250	pF	
Output	Operating supply voltage	V_{CC}	–	4.5	–	35	V	
	Low level output voltage	V_{OL}	$I_F=10\text{mA}$, $I_O=2.4\text{mA}$	–	0.3	0.6	V	
	Low level output current	I_{OL}	$I_F=10\text{mA}$, $V_O=0.6\text{V}$	4.4	9	–	mA	
	High level output current	I_{OH}	$I_F=0$, $V_{CC}=V_O$	–	5	50	μA	
	High level supply current	I_{CCH}	$I_F=0$, $V_O=\text{OPEN}$	–	0.6	1.3	mA	
	Low level supply current	I_{CCL}	$I_F=10\text{mA}$, $V_O=\text{OPEN}$	–	0.8	1.3	mA	
Transfer characteristics	"High→Low" threshold input current	I_{FHL}	$V_O=0.8\text{V}$, $R_L=20\text{k}\Omega$, $V_{CC}=15\text{V}$	–	1.5	5	mA	
	Isolation resistance	R_{ISO}	$T_a=25^\circ\text{C}$, $\text{DC}500\text{V}$, 40 to 60%RH	5×10^{10}	10^{11}	–	Ω	
	Floating capacitance	C_f	$T_a=25^\circ\text{C}$, $V=0$, $f=1\text{MHz}$	–	0.6	1	pF	
	Response time	^{*8} "High→Low" propagation time	t_{PHL}	$I_F=10\text{mA}$ (t_{PHL}), $I_i=0$ (t_{PLH}), $V_{CC}=15\text{V}$, $R_L=20\text{k}\Omega$, $C_L=100\text{pF}$ $V_{THLH}=2.0\text{V}$, $V_{THHL}=1.5\text{V}$	30	210	400	ns
		^{*8} "Low→High" propagation time	t_{PLH}		270	400	550	ns
		^{*7} Distortion of pulse width	Δtw		–	190	450	ns
	Propagation delay difference between any two parts	T_{PSK}	–150		200	450	ns	
CMR	^{*9} Instantaneous common mode rejection voltage "Output : High level"	CM_H	$T_a=25^\circ\text{C}$, $I_F=0$, $V_{CC}=15\text{V}$, $C_L=100\text{pF}$, $V_{CM}=1.5\text{kV}_{(P-P)}$, $R_L=20\text{k}\Omega$, $V_O>3.0\text{V}$	15	30	–	kV/ μs	
	^{*9} Instantaneous common mode rejection voltage "Output : Low level"	CM_L	$T_a=25^\circ\text{C}$, $I_F=10\text{mA}$, $V_{CC}=15\text{V}$, $C_L=100\text{pF}$, $V_{CM}=1.5\text{kV}_{(P-P)}$, $R_L=20\text{k}\Omega$, $V_O<1.0\text{V}$	–15	–30	–	kV/ μs	

^{*6} It shall connect a by-pass capacitor of $0.01\mu\text{F}$ or more between V_{CC} (Pin ⑥) and GND (Pin ③) near the device, when it measures the transfer characteristics and the output side characteristics

^{*7} Distortion of pulse width $\Delta\text{tw} = |t_{PHL} - t_{PLH}|$

^{*8} Refer to Fig.1

^{*9} Refer to Fig.2

■ Recommended Operating Conditions

Parameter	Symbol	MIN.	MAX.	Unit
Forward current	I_F	10	20	mA
Supply voltage	V_{CC}	4.5	35	V
Output voltage	V_O	0	35	V
Operating temperature	T_{opr}	–40	100	$^\circ\text{C}$

Fig.1 Test Circuit for t_{PHL} and t_{PLH}

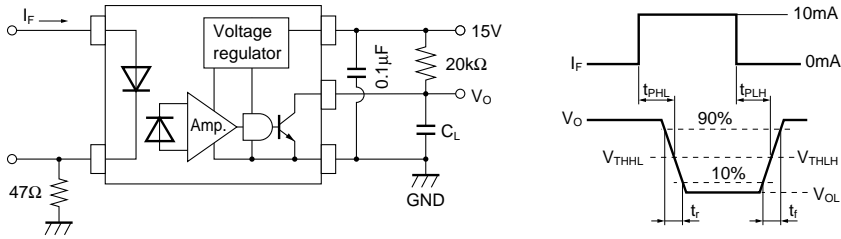


Fig.2 Test Circuit for CM_H and CM_L

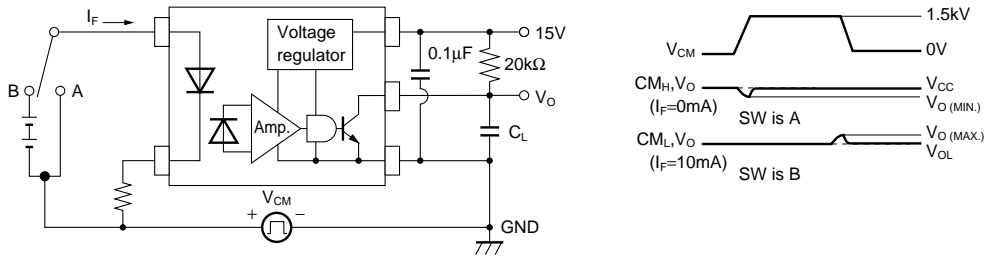


Fig.3 Forward Current vs. Ambient Temperature

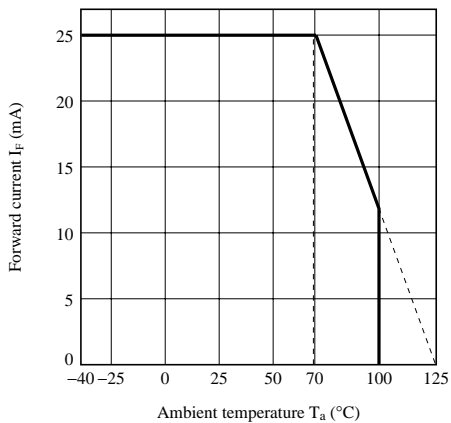


Fig.4 Power Dissipation vs. Ambient Temperature

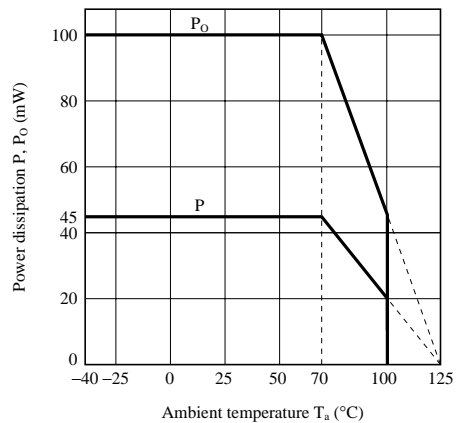


Fig.5 Output Current vs. Forward Current

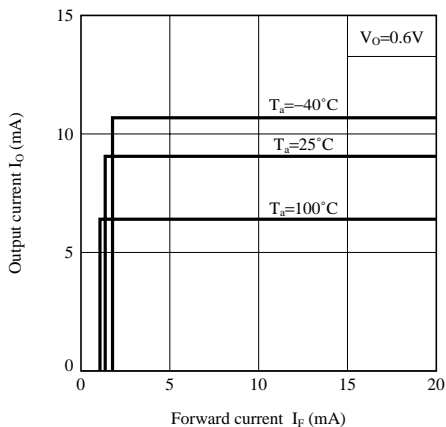


Fig.6 Forward Current vs. Forward Voltage

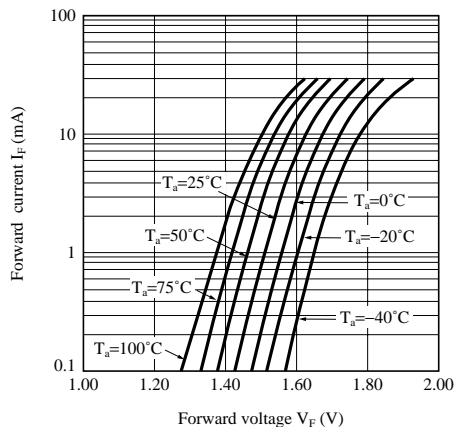


Fig.7 Relative Output Current vs. Ambient Temperature

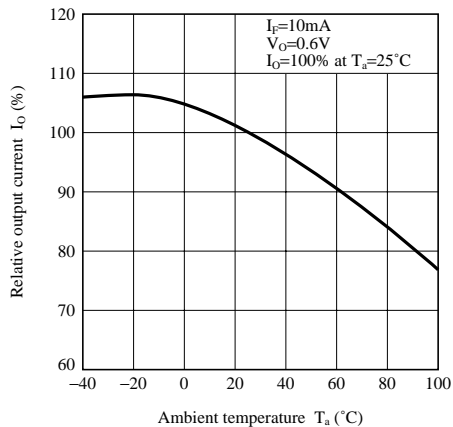


Fig.8 Threshold Input Current vs. Ambient Temperature

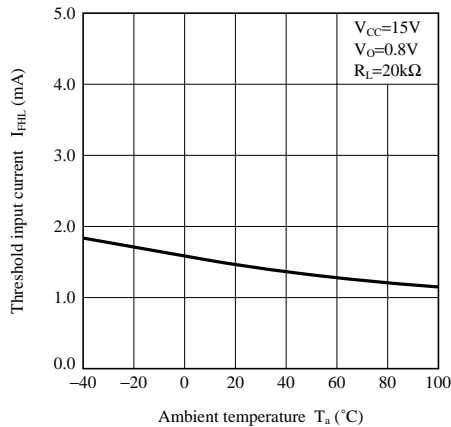


Fig.9 Low Level Output Voltage vs. Ambient Temperature

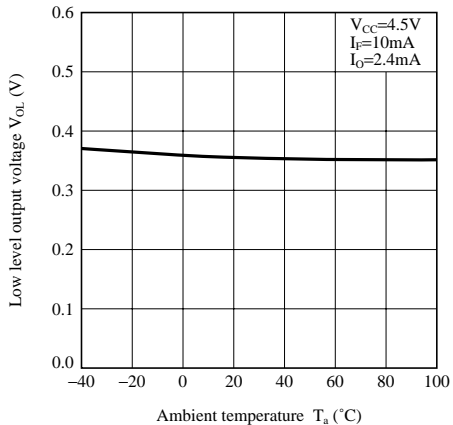


Fig.10 Supply Current vs. Ambient Temperature

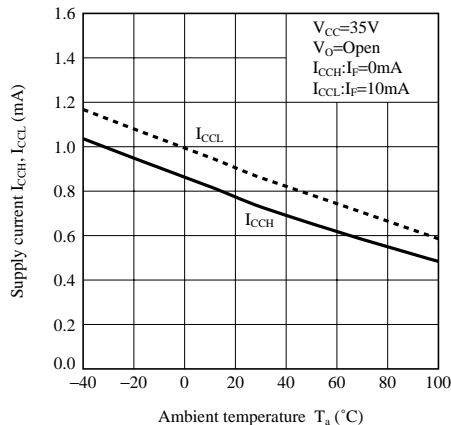


Fig.11 Propagation Delay Time vs. Ambient Temperature

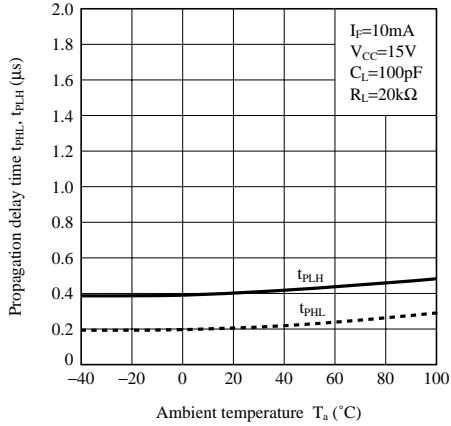


Fig.12 Propagation Delay Time vs. Load Resistance

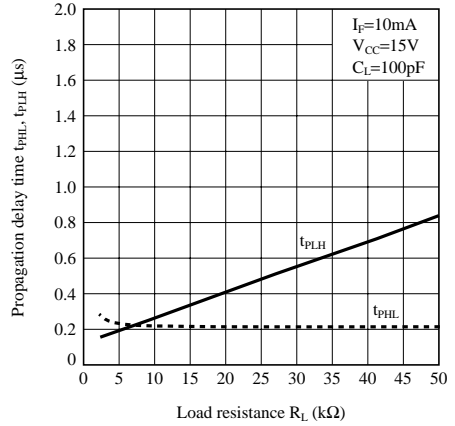


Fig.13 Propagation Delay Time vs. Load Capacitance

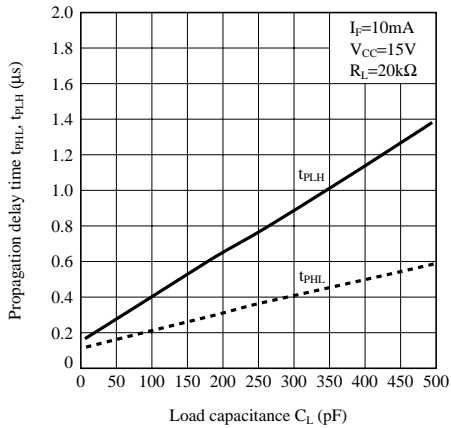


Fig.14 Propagation Delay Time vs. Supply Voltage

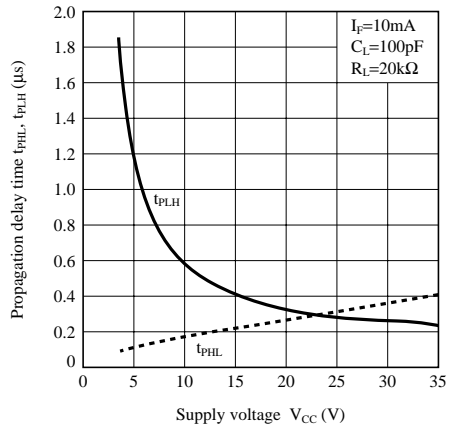
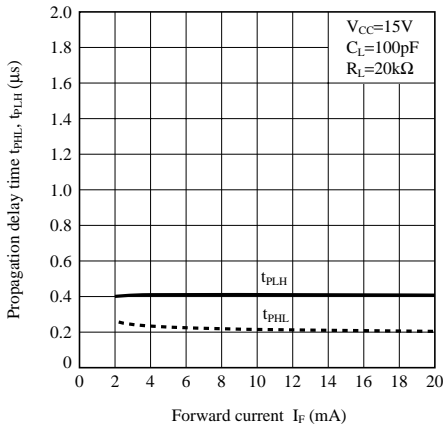


Fig.15 Propagation Delay Time vs. Forward Current



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